

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/613,598	TAKANO, KENICHI	
Examiner	Art Unit	
Tianjie Chen	2656	

SEARCHED					
Class	Subclass	Date	Examiner		
Updated		2/6/2006	ΤJ		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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